

Form PTO 1449  U.S. Department of Commerce Patent and Trademark Office.  Information Disclosure Statement by Applicant	ATTY. DOCKET NUMBER <b>NITT.0161</b>	SERIAL NUMBER <b>To Be Assigned 10/699,853</b> <i>cml</i>
	APPLICANT <b>Shichi et al</b>	
	FILING DATE <b>Concurrently Herewith</b>	GROUP <b>2881</b>

**U.S. Patent Documents**

Examiner Initial	Cited by Examiner in Parent	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE
<i>cml</i>	X	6,039,000	3/21/2000	Libby et al.			2/11/98
<i>cml</i>	X	5,270,552	12/14/93	Ohnishi et al.			8/21/92
<i>cml</i>	X	5,986,264	11/16/99	Grunewald			4/22/96
<i>cml</i>	X	5,089,774	2/18/92	Nakano			12/24/90

**Foreign Patent Documents**

Examiner Initial	Filed In Parent	DOCUMENT NUMBER	FILING DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION	
							YES	NO
<i>cml</i>	X	05-052721	8/22/91	Japan			Abstract	X
<i>cml</i>	X	WO99/05506	7/21/98	WO			Abstract	X
<i>cml</i>	X	03-166744	11/27/89	Japan			Abstract	X

**Other Documents (Including Author, Title, Date Pertinent Pages, Etc.)**

Filed in Parent		
<i>cml</i>	X	L.A. Giannuzzi, J.I. Drown, S.R. Brown, R. B. Irwin, F.A. Stevie, "Focused Ion Beam Milling and Micromanipulation Lift-out for Site Specific Cross-Section TEM Specimen Preparation", Material Research Society Symposium Proceeding (1997), Vol, 480, pp. 19-27.
<i>cml</i>	X	L.R. Herlinger, S. Chevacharoenkul, D.C. Erwin, "TEM Sample Preparation Using a Focused Ion Beam and a Probe Manipulator", Proceedings of the 22 <sup>nd</sup> International Symposium for Testing and Failure Analysis, 18-22 November 1996, pp. 199-205
<i>cml</i>	X	"Election and Ion Beam Handbook", Third Edition, (Japan Society for the Promotion of Science, 132 commission, Nikkan Kogyo ShinbunSha), pp. 458-461

EXAMINER <i>Chris Lalwood</i>	DATE CONSIDERED <b>04/23/04</b>
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EXAMINER: Initial if citation is considered, whether or not citation is in conformance with MPEP 609; draw a line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant